

## Product Change Notice

**Issue Date:** 30-March-2021**Change Description:**

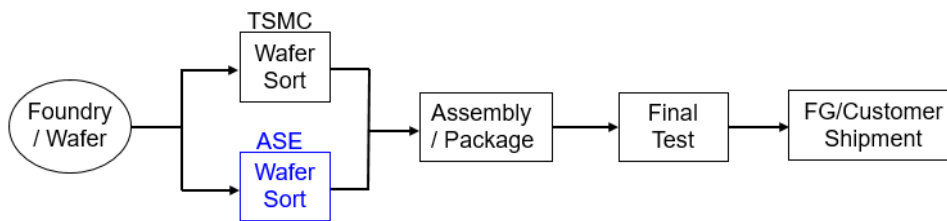
Add ASE-KH as a 2<sup>nd</sup> source wafer sort (i.e. wafer probe) site

**Parts Affected:**

BCM89200BBQLEGT  
BCM89200BBQLEG  
BCM89200BPBGT  
BCM89200BPBG  
BCM89500BQLEG  
BCM89500BBQLEGT  
BCM89500BBQLEG  
BCM89501BQLEG  
BCM89501BBQLEGT  
BCM89501BBQLEG  
BCM89501BPBG

**Description and Extent of Change:**

Electrical wafer sort testing is currently performed on this product at TSMC Fab 14 (Tainan, Taiwan R.O.C.). Broadcom will add ASE-KH (Kaohsiung City, Taiwan R.O.C.) as a 2<sup>nd</sup> source for wafer sort. There is no change to Foundry, Assembly or Final Test – see updated flow below.



Note that ASE-KH is a Broadcom qualified automotive wafer sort supplier.

**Reasons for Change:**

Increase wafer sort capacity and flexibility

**Effect of Change on Fit, Form, Function, Quality, or Reliability:**

The device specification, test limits, SYA/SBL limits, and D-PAT will remain the same, which will ensure product electrical performance remains the same. Appropriate correlation has been performed to ensure no impact on Fit, Form, Function, Quality, or Reliability. In addition, the devices are fully tested at Hot and Cold temperature at Final Test.

**Effective Date of Change:**

Product shipments using this change will begin after **15-Jun-2021**. Timing of shipment of parts tested at ASE-KH will vary by part number depending on customer demand and inventory levels.



**Correlation Information:**

The TSMC-to-ASE correlation activity has successfully completed. See the table below for details.

Note: All of the part numbers listed in this PCN are from the same device family and use the same test hardware.

<b>Correlation Item</b>	<b>ASE-KH Result</b>	<b>OK/NOK</b>
<b>Tester</b>	Same as at TSMC	OK
<b>Test DIB and probe card</b>	Same as at TSMC	OK
<b>Test Program</b>	Same as at TSMC	OK
<b>Test time / # of tests</b>	Same as at TSMC	OK
<b>SYA/SBL limits</b>	Same as at TSMC	OK
<b>D-PAT limits</b>	Same as at TSMC	OK
<b>Loop 50 times; 5 units/site (2 sites) @ Room Temp</b>	500/500 Pass	OK
<b>Run 1 correlation wafer (yield/reject comparison)</b>	Pass	OK
<b>Analog test parameter correlation</b>	Pass	OK

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Please contact your Broadcom field sales engineer or Contact Center for any questions or support requirements. Please return any response as soon as possible, but **not to exceed 30 days**.